PCN Number: 2019			90206001.1 <mark>A</mark>		PCN Date:		:	Apr 22, 2019			
Title: Qualification of RFA			AB as an additional Fab site option for select devices								
<b>Customer Contact:</b>			PCN Manager		Dept:			Quality Services			
Proposed 1 <sup>st</sup> Ship Date:			May 2, 2019 Estima Availab		ited Sample bility:		le	Date provided at sample request.			
Change Type:											
Assembly Site				Assembly Process				Assembly Materials			
	Desigr	า			Electrical Specification				Mechanical Specification		
	Test S	ite			Packing/Shipping/Labeling				Test Process		
☐ Wafer Bump Site				Wafer Bump Material				Wafer Bump Process			
			$\boxtimes$	Wafer Fab Materials				Wa	fer Fab Process		
				Part number change							
PCN Details											

## **Description of Change:**

Revision A is to announce the addition of new devices that were not included on the original PCN notification. These new devices are highlighted in **bold** in the device list below. The expected first shipment date for these new devices specifically, will be 90 days from this notice (July 22, 2019). The proposed 1<sup>st</sup> ship date of May 2, 2019 still applies for the original set of devices.

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab source for the selected devices listed in the "Product Affected" section.

С	urrent Fab Site	9	Additional Fab Site			
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter	
MIHO8	LBC7	200 mm	RFAB	LBC7	300 mm	

Qual details are provided in the Qual Data Section.

## **Reason for Change:**

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

# Changes to product identification resulting from this PCN:

# **Current:**

Current Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
MIHO8	MH8	JPN	Ibaraki

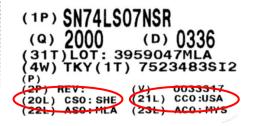
## **New Fab Site:**

New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
RFAB	RFB	USA	Richardson

Sample product shipping label (not actual product label)







Product Affected:									
DRV8846RGER	DRV8846RGET	DRV8848PWP	DRV8848PWPR						
DRV8848LPWPR									

## Qualification Report

## Approve Date 05-Apr-2019

### Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: DRV8848PWPR	QBS Product Reference: <u>DRV8846RGER</u>	QBS Product Reference: <u>DRV8848PWP</u>	QBS Process Reference: <u>TPS62110RSA</u>	QBS Package Reference: SN0508073PW	QBS Package Reference: TPA6011A4PWP	QBS Package Reference: <u>TPS51117PW</u>
-	Yield Evaluation	(per mfg. Site specification)	1/Pass	-	-	-	-	-	-
AC	Autoclave 121C	240 Hours	-	-	-	3/231/0	-	-	-
AC	Autoclave 121C	96 Hours	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
CDM	ESD - CDM	1500 V	-	1/3/0	1/3/0	-	-	-	-
DPA	Destructive Physical Analysis	Post 500 Temp Cycle	-	-	-	-	-	3/9/0	-
ED	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	-	-
ELFR	Early Life Failure Rate, 140C	48 Hours	-	-	-	3/1881/0	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	3/231/0	-	-	-
НВМ	ESD - HBM	4000 V	-	1/3/0	-	-	-	-	-
HTOL	Life Test, 140C	480 Hours	-	-	-	3/231/0	-	-	-
HTOL	Life Test, 155C	240 Hours	-	-	-	-	-	3/231/0	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
LU	Latch-up	(per JESD78)	-	1/6/0	-	-	-	-	-
TC	Temperature Cycle, -65/150C	1000 Cycles	-	1/77/0	-	3/231/0	-	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	1/77/0	1/77/0	3/231/0	3/231/0	3/231/0	3/231/0

- QBS: Qual By Similarity
- Qual Device DRV8848PWPR is qualified at LEVEL3-260CG
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: <a href="http://www.ti.com/">http://www.ti.com/</a>

#### Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

#### **Qualification Report**

### Approve Date 29-Jan-2019

#### **Qualification Results** Data Displayed as: Number of lots / Total sample size / Total failed

				QBS Product	QBS Product	QBS Process		QBS Package
Type	Test Name /	Duration	Qual Device:	Reference:	Reference:	Reference:	QBS Package Reference:	Reference:
.,,,,	Condition		DRV8846RGER	DRV8846RGER	DRV8848PWP	TPS51217DSC	TP\$2231RGPR CU WIRE	TPS62402DRCR CU W
4.0	Auto doue 4040	0.40.11				0/400/0	0.004.0	IRE
AC	Autoclave 121C	240 Hours	-	-	-	6/462/0	3/231/0	1/77/0
AC	Autoclave 121C	96 Hours	-	-	-	6/462/0	3/231/0	1/77/0
CDM	ESD - CDM	1000 V	-	-	-	3/9/0	-	-
CDM	ESD - CDM	1500 V	-	1/3/0	1/3/0	3/9/0	-	-
CDM	ESD - CDM	250 V	-	1/3/0	-	3/9/0	-	-
DS	Die Shear		-	-	-	-	3/30/0	1/10/0
ED	Electrical Characterization	Per Datasheet Parameters	1/Pass	1/30/0	1/30/0	3/60/0	-	-
HAST	Biased HAST 130C/85%RH	96 Hours	-	-	-	3/231/0	-	-
HBM	ESD - HBM	1000 V	-	1/3/0	-	3/9/0	-	-
HBM	ESD - HBM	1500 V	-	1/3/0	-	2/6/0	-	-
HBM	ESD - HBM	2000 V	-	1/3/0	-	3/9/0	-	-
HBM	ESD - HBM	4000 V	-	1/3/0	-	-	-	-
HBM	ESD - HBM	500 V	-	1/3/0	-	3/9/0	-	-
HTOL	Life Test, 135C	635 Hours	-	-	-	3/231/0	-	-
HTOL	Life Test, 155C	240 Hours	-	-	-	-	3/231/0	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	-	3/231/0	3/231/0	1/77/0
LU	Latch-up	(per JESD78)	-	1/6/0	-	3/18/0	-	-
MISC	Salt Atmosphere	24 Hours	-	-	-	-	3/66/0	1/22/0
PD	Physical Dimensions	-	-	-	-	-	3/15/0	1/5/0
SD	Solderability	8 Hours Steam Age	-	-	-	-	3/66/0	-
TC	Temperature Cycle -65/150C	1000 Cycles	-	1/77/0	-	3/231/0	3/231/0	1/77/0
TC	Temperature Cycle -65/150C	500 Cycles	-	1/77/0	1/77/0	3/231/0	3/261/0	1/87/0
TC- SAM	Post Temp Cycle SAM	CSAM and TSAM analysis after 1000 cycles Temp cycle	-	-	-	3/36/0	-	-
WBP	Bond Pull	Wires	-	-	-	-	3/228/0	1/76/0
WBS	Bond Shear	Wires	-	-	-	-	3/228/0	1/76/0
XRAY	X-ray	(top side only)	-	-	-	3/15/0	3/15/0	1/5/0

<sup>-</sup> QBS: Qual By Similarity

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN www admin_team@list.ti.com

<sup>-</sup> Qual Device DRV8846RGER is qualified at LEVEL3-260C

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

<sup>-</sup> The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours - The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles